

<b>Notice of References Cited</b>	Application/Control No. 10/611,633	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner David A. Reifsnyder	Art Unit 1723	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,946,410 B2	09-2005	French et al.	977/DIG.1
*	B	US-6,790,425 B1	09-2004	Smalley et al.	977/DIG.1
*	C	US-6,683,783 B1	01-2004	Smalley et al.	361/502
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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